Photoluminescence Inspection

光致发光检测设备

Photoluminescence(PL)could measure Intesnsity, FWHM and wavelength distribution of photoluminescence. It could detect impurity level and defect, composite mechanism, and material quality identification.

光致发光主要对材料能带结构，杂质浓度和缺陷，组分机理以及材料质量进行检测。

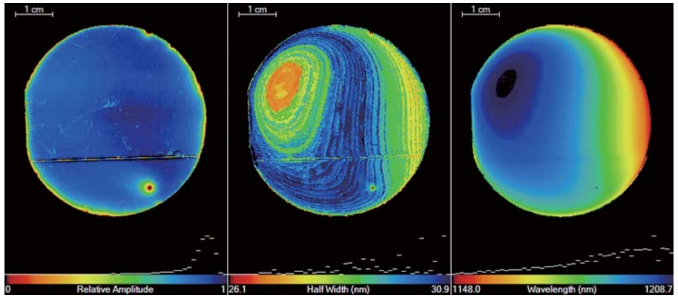
WT-2000PL is professional equipment to test PL, and integrated multiple functions. Its feature Non-contact, High-speed, and Customization.

WT-2000PL专门针对PL应用开发，具有非接触，快速，可变温，微光斑等特点。

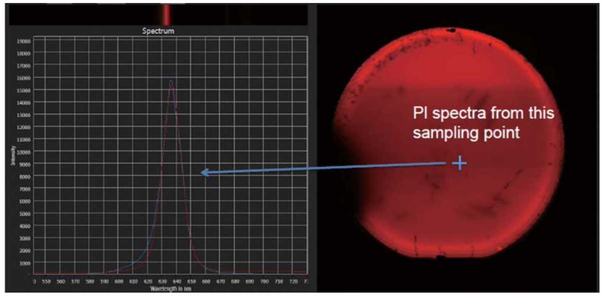
Capability:

- Micro spot 微光斑
- Selectable laser source 激发光波长可选
- High resolution PL mapping 高分辨率PL扫描
- Optional cryostat for laboratory applications 适合科研的变温扫描

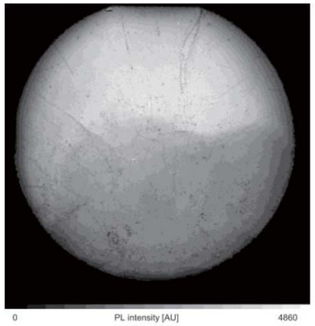
WT-2000PL



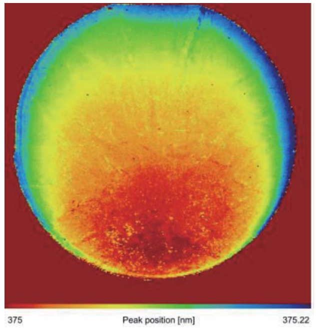
PL of GaN :Intensity,FWHM,wavelengh



Spectral info from every point of wafer



PL intensity mapping show defect



PL peak positon mapping show non-uniformity in Eg